NANO
Research Infrastructure

Atomic Force Microscope	**Category:** **C. Particle Characterisation in and ex-situ** **Institute: VITO** **Location: Boeretang 200, 2400 Mol, Belgium** **Contact Details of Technology Expert:** **Rosita Persoons** **Phone: +32 (0)14 335730** **Fax: +32 (0)14 321186** **E-mail: rosita.persoons@vito.be**

Short technology description

The Veeco Dimension 3100 Scanning Probe Microscope produces high-resolution, three-dimensional images by scanning a sharp tip over the sample surface.

Main Features (Equipment Capabilities):

- Nanoscope Dimension 3100 Controller
- Nanoscope IVIIIa Scanning Probe Microscope Controller
- Different cantilever probes (Si_3N_4, etched Si_3N_4 , gold coated tips) are available for different modes :
  - Contact AFM in air and fluids
  - Tapping mode in air and fluids
  - Lateral Force Mode
  - Force imaging
- Easily changes among all AFM/STM scanning modes/techniques without tools

Typical Samples & Images:

Any further Information: